

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1099056	(wafer\$1 or semicondutor\$I or chip\$I or substrat\$I or IC or intergrated adj circuit or PCB or printed adj circuit adj board or PWB or printed adj wiring)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/28 13:06
L2	2	L1 and (detect\$3 or determine)same(defect or flaw or fault or reject\$3)with microfabricat\$2 near3 structures	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/28 13:10
L3	43	L1 and (detect\$3 or determine)same(defect or flaw or fault or reject\$3)with(repetitive or non adj repetitive)same(area or regions)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/28 13:12
L4	26	L3 and @ad<"20011024"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/28 13:13
L5	43	L1 and (detect\$3 or determine)same(defect or flaw or fault or reject\$3)with repetitive same(area or regions)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/28 13:12
L6	26	L5 and @ad<"20011024"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/28 13:13
L7	0	L6 and creat\$3 same (1D or one adj dimensional\$1 or 1-D)same(cell or array or matrix)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/28 13:17
L8	0	L6 and creat\$3 same (1D or one adj dimensional\$1 or 1-D)same(cell or array or matrix)same(contrast or threshold or brightness)with histogram	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/28 13:19

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	314623	(wafer\$1 or semicondudor\$I or chip\$I or substrat\$I or IC or intergrated adj circuit or PCB or printed adj circuit adj board or PWB or printed adj wiring or microfabricat\$3 near3 structures)	USPAT	OR	ON	2005/12/28 14:27
L2	14	L1 and (detect\$3 or determine)same(defect or flaw or fault or reject\$3)with(repetitive or non adj repetitive)same(area or regions)and coordinat\$4	USPAT	OR	ON	2005/12/28 15:46
L3	1801	L1 and creat\$3 and (1D or one adj dimensional\$1 or 1-D)same(cell or array or matrix)	USPAT	OR	ON	2005/12/28 15:09
L4	192	L3 and creat\$3 and (1D or one adj dimensional\$1 or 1-D)same(cell or array or matrix)same(contrast or brightness or intensity or threshold)	USPAT	OR	ON	2005/12/28 15:11
L5	7	L3 and creat\$3 and (1D or one adj dimensional\$1 or 1-D)same(cell or array or matrix)same(contrast or brightness or intensity or threshold)same (histogram or profile)	USPAT	OR	ON	2005/12/28 15:53
L6	4508	382/145,141,149,168,274,254,232, 151,286.ccls.	USPAT	OR	ON	2005/12/28 15:44
L7	0	L5 and (detect\$3 or determine)same(defect or flaw or fault or reject\$3)with(repetitive or non adj repetitive)same(area or regions)and coordinat\$4	USPAT	OR	ON	2005/12/28 15:45
L8	0	L4 and (detect\$3 or determine)same(defect or flaw or fault or reject\$3)with(repetitive or non adj repetitive)same(area or regions)and coordinat\$4	USPAT	OR	ON	2005/12/28 15:45
L9	8	L4 and (detect\$3 or determine)and(defect or flaw or fault or reject\$3)and(repetitive or non adj repetitive)and(area or regions)and coordinat\$4	USPAT	OR	ON	2005/12/28 15:49
L10	0	L6 and L9	USPAT	OR	ON	2005/12/28 15:47
L11	0	356/388,394,429,237.2,237.5,237.5, "237".4.ccls.	USPAT	OR	ON	2005/12/28 15:48
L12	2235	356/388,394,429,237.2,237.5,237.5, 237.4.ccls.	USPAT	OR	ON	2005/12/28 15:48
L13	4	L4 and L12	USPAT	OR	ON	2005/12/28 15:54
L14	4	L4 and L6	USPAT	OR	ON	2005/12/28 15:50
L15	0	L14 and L5	USPAT	OR	ON	2005/12/28 15:59

L16	7	L4 and L5	USPAT	OR	ON	2005/12/28 15:51
L17	0	L12 and L5	USPAT	OR	ON	2005/12/28 15:53
L18	592	250/559.22,559.45.ccls.	USPAT	OR	ON	2005/12/28 15:54
L19	0	L4 and L18	USPAT	OR	ON	2005/12/28 15:54
L20	0	257/184,E21.525,E21.553.ccls	USPAT	OR	ON	2005/12/28 15:56
L21	559	257/184.ccls.	USPAT	OR	ON	2005/12/28 15:56
L22	0	257/184,E21.525,E21.53.ccls	USPAT	OR	ON	2005/12/28 15:56
L23	0	257/184,21.525,21.53.ccls	USPAT	OR	ON	2005/12/28 15:57
L24	0	257/184,E "21.525,E" "21.53.ccls"	USPAT	OR	ON	2005/12/28 15:58
L26	1955	257/184,E21.525,E21.53.ccls.	USPAT	OR	ON	2005/12/28 15:58
L27	1	L4 and L26	USPAT	OR	ON	2005/12/28 16:00
L28	0	L27 and L5	USPAT	OR	ON	2005/12/28 15:59
L29	1	L27 and @ad<"20011024"	USPAT	OR	ON	2005/12/28 16:00

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	272	(wafer\$1 or semicondudor\$I or chip\$I or substrat\$I or IC or intergrated adj circuit or PCB or printed adj circuit adj board or PWB or printed adj wiring or microfabricat\$3 near3 structures)and creat\$3 and(1D or one adj dimensional\$1 or 1-D)and(cell or array or matrix)and(contrast or brightness or intensity or threshold)and (histogram or profile).clm.	US-PGPUB	OR	ON	2005/12/28 16:12
L2	3	(wafer\$1 or semicondudor\$I or chip\$I or substrat\$I or IC or intergrated adj circuit or PCB or printed adj circuit adj board or PWB or printed adj wiring or microfabricat\$3 near3 structures)and creat\$3 and(1D or one adj dimensional\$1 or 1-D)and(cell or array or matrix)and(contrast or brightness or intensity or threshold)and(histogram or profile)and(repetitive or non adj repetitive)same(areas or regions).clm.	US-PGPUB	OR	ON	2005/12/28 16:14
L3	0	L2 and @ad<"20011024"	US-PGPUB	OR	ON	2005/12/28 16:15